

Figure 1 Contour plots of real-time GISAXS intensity evolution of InN/a-sapphire at 250 °C. X-ray incidence and exit angles are 0.8 and 0.2 degrees.

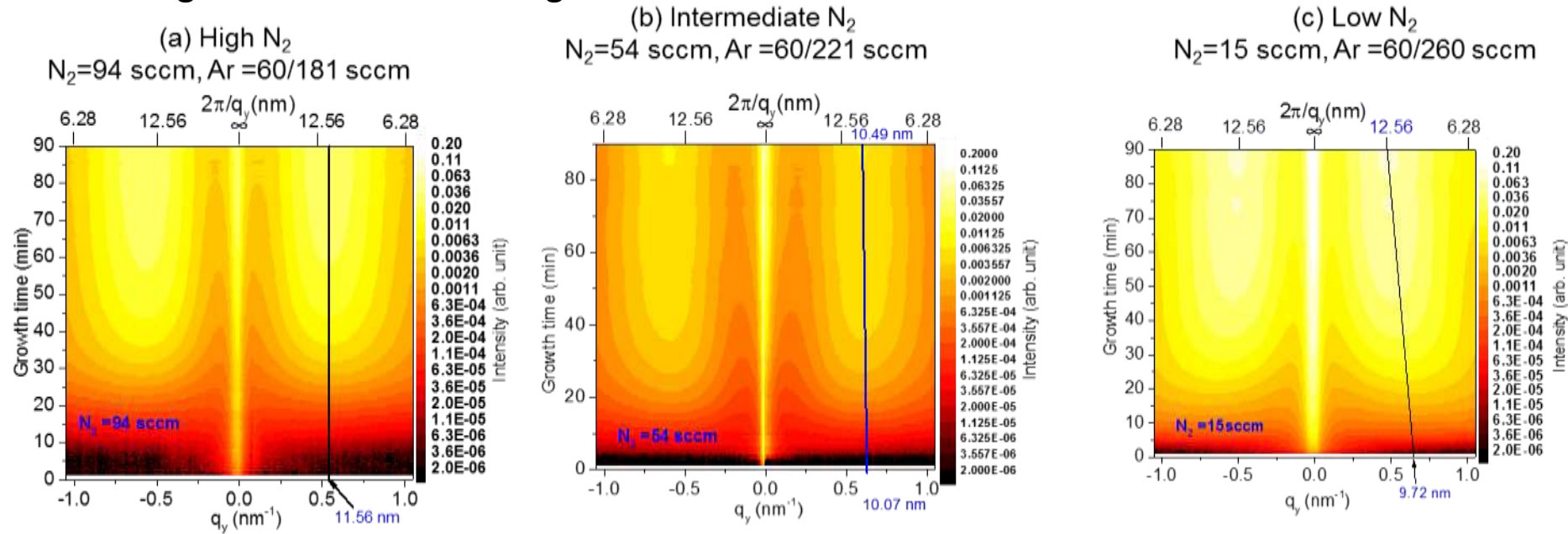


Figure 2 *Ex situ* measured AFM surface morphology.

